

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	
	:	
Raymond Payette	:	
	:	
Serial No. <i>New Application</i>	:	Group Art Unit: <i>Unassigned</i>
	:	
Filed: April 2, 2004	:	Examiner: <i>Unassigned</i>
For:		
INTERFEROMETRIC MODULATION PIXELS AND MANUFACTURING METHOD TEHEROF		

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

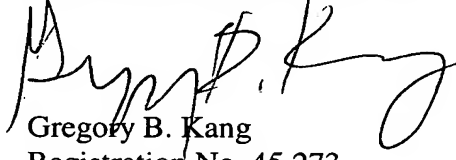
No further elaboration is believed necessary. Copies of the documents are submitted herewith in accordance with 37 C.F.R. §1.98(a).

AUTHORIZATION

This Information Disclosure Statement is being filed before receipt of the first Office Action. No fee is required. The Commissioner is hereby authorized to charge any additional fees which may be required for this submission, or credit any overpayment to deposit account no. 50-2036.

Respectfully submitted,

BAKER & HOSTETLER LLP


Gregory B. Kang
Registration No. 45,273

Date: 4-2-04
Baker & Hostetler LLP
Washington Square, Suite 1100
1050 Connecticut Avenue, N.W.
Washington, D.C. 20036
Telephone: (202) 861 1500
Facsimile: (202) 861 1783

LIST OF ART CITED BY APPLICANT (PTO-1449)					ATTY. DOCKET NO. 87391.1000		SERIAL NO. Unassigned	
					APPLICANT LIN, Wen-Jian, et al.			
					FILING DATE 4/2/04		GROUP Unassigned	
U.S. PATENT DOCUMENTS								
	EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
A		5,835,255	10 Nov 1998	Miles	359/291	359/578	5 May 1994	
B								
C								
D								
E								
F								
G								
H								
I								
J								
K								
L								
M								
N								
O								
P								
Q								
R								
S								
T								
FOREIGN PATENT DOCUMENTS								
	EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
U								
V								
W								
X								
Y								
Z								
AA								
BB								
CC								
DD								
EE								
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
FF								
GG								
HH								
II								
JJ								
EXAMINER					DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered.
 Include copy of this form with next communication to Applicant.